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MEDIA INFORMATION

Fast, Affordable Material ID with Vanta Element XRF

The new Vanta Element XRF analyzer offers the essential features that the Vanta series is known for – speed, reliability, ruggedness, connectivity and smartphone-like ease of use – in a cost-effective model. Easy to learn, fast to use and weighing a slim 1.32 kg, the Vanta Element analyzer is up to the challenge of all day, high-throughput testing.

Hamburg, 11 September 2019 – The Vanta Element handheld X-ray fluorescence (XRF) analyzer offers speed and ease of use in a variety of testing environments, including scrap recycling and metal manufacturing. Users can obtain clear material and grade identifications in seconds and compare alloy grades on the instrument’s screen. With a dual-core processor and powered by Olympus’ proven Axon technology, the Vanta Element analyzer has the same stability and resolution as the rest of the Vanta series for rapid sorting and a fast return on investment.

Built for use in demanding environments, Vanta Element analyzers are IP54-rated for resistance to dust and moisture and constructed to pass a 4-foot drop test (MIL-STD-810G) to help keep you working in case of an accidental drop or impact. For additional protection, a stainless steel faceplate is paired with a thick (50 µm) Kapton® window that can be easily attached and removed for toolless window changes in the field. If you work in hot or cold environments, you can count on the Vanta Element analyzer to perform continuously in temperatures from -10 to 45 °C.

The analyzer’s ruggedness features are paired with optional wireless connectivity. Connect to the Olympus Scientific Cloud for wireless data sharing and access to convenient fleet management tools, the Olympus mobile app or your network, helping future proof it for Industry 4.0. The analyzer also has an industrial 1 GB microSD™ card for storing results and two USB ports for easy data export. For added flexibility, the Vanta Element analyzer is compatible with accessories including the Vanta field stand, soil foot, probe shield and holster.

For more information about the Vanta Element handheld XRF analyzer or any of Olympus' other industrial solutions, visit www.olympus-ims.com.

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Please contact:

Olympus:
Jennifer Giesen (Content Marketing Manager Industry EMEA)
Olympus Europa SE & Co. KG
Hamburg, Germany
Tel: +49 (0) 40 23773 4256
Email: scientificsolutions@olympus-europa.com
Web: www.olympus-ims.com

Text:
Victoria Coupe (Senior Account Manager)
Alto Marketing
Fareham, UK
Tel: +44 (0) 1489 557 672
Email: victoriac@alto-marketing.com
Web: www.alto-marketing.com

Olympus media contact in the USA:
Kristin Schaeffer
Klunk & Millan Advertising
kristin@klunkmillan.com
610-973-2400